

ISSUE CLASSIFICATION	
Class	Section

PATENT NUMBER

U.S. UTILITY Patent Application

KU ^{ONE} PG 4
 SCANNED ~~4/10/03~~ O.A. *[Signature]*

PATENT DATE

APPLICATION NO.	CONT/PRIOR	CLASS	SUBCLASS	ART UNIT	EXAMINER
09/800495	F	451 <i>459</i>	<i>608</i>	3723 <i>PLS</i>	<i>EV HOSSEN</i>

APPLICANTS

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TITLE

Method of detecting and measuring endpoint of polishing processing and its apparatus and method of manufacturing semiconductor device using the same

Maaz Eronini

[illegible]

<input type="checkbox"/> TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
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